



PATENT
32860-000214/US



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: **Joachim BAUMANN et al.**

Serial No.: **09/762,508** Group: **2878**

Filed: **February 7, 2001** Examiner: **A. J. Gagliardi**

For: **THERMAL WAVE MEASURING METHOD**

AMENDMENT

Assistant Commissioner for Patents
Washington, D.C. 20231

January 6, 2002

Sir:

Responsive to the Office Action mailed **July 5, 2002**, the following amendments and remarks are respectfully submitted in connection with the above-identified application. A Request for Extension of Time is attached hereto and incorporated by reference, thereby extending the date from October 5, 2002 to January 6, 2003 (January 5, 2003 being a Sunday).

IN THE CLAIMS

Please amend the claims as follows.

B1

1. (Twice Amended) A thermal wave measuring method for contact-free measurement of geometrical or thermal features of a layer structure, comprising the steps of:
simultaneously driving a modulatable heat source with at least two predetermined discrete and differently modulated frequencies, thereby periodically heating said layer structure;
receiving infrared radiation emitted by said layer structure that is correspondingly modulated in intensity; and